

Deep-submicron FD-SOI for front-end application

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Abstract

In order to confirm benefits of a deep sub-micron FD-SOI and to identify possible issues concerning front-end circuits with the FD-SOI, we have submitted a small design to OKI via the multi-chip project service of VDEC, the university of Tokyo. The initial test results and future plan for development are presented.

Key words: FD-SOI, deep-submicron CMOS, CMOS analog, front-end, radiation effect

1. Introduction

The SOI CMOS process has long been employed for special uses in such areas as military and/or space instrumentations. The development of a bulk CMOS process, however, significantly advanced over the SOI CMOS, and, then, the SOI CMOS have not been widely employed in commercial use. Entering into the late 1990s, the trend curve of bulk CMOS processes has tended to be behind Moore's law, and, hence, manufactures are eager to find a way to recover development speed. SOI CMOS is revisited to exhibit its performance over existing bulk CMOS processes; the SOI CMOS eventually shows up as a successor to the CMOS process and inheriting well-matured fabrication technologies for bulk CMOS.

SOI devices are free from parasitic PNP structure, and, hence, intrinsically immune to single event latch-ups. Moreover SOI devices are located on a very thin silicon layer, the energy deposit by impinging particle is relatively small, and, then, it appears that the single event upsets and/or single-event transient are automatically mitigated. The reality is that the SEU and/or SET effects are not necessarily eliminated even in an advanced SOI process[1,2] without adoption of an appropriate hardening-by-design technology.

When designing front-end circuits with an FD-SOI, we can take benefits such as small floating-body effect, superior sub-threshold characteristics and small temperature coefficient as well as common nature of SOI devices, i.e. small parasitic capacitance, low junction leakage, decrease in substrate coupling noise, and reduction of silicon area. In com-

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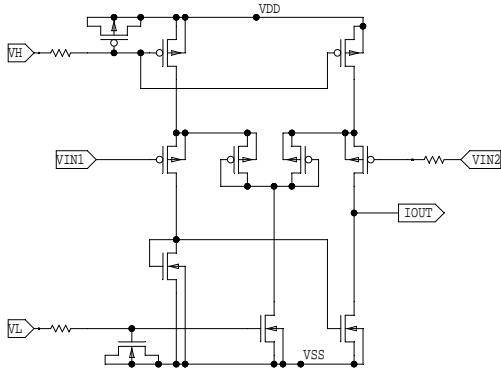


Fig. 3. Schematic of the feedback element for CHAIN1.

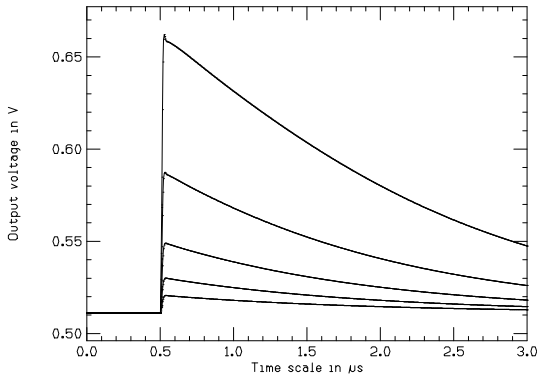


Fig. 4. Waveform for a slow tail operation of CHAIN1. The feedback circuit is operated with a bias current of 1 nA . The curves are for input charges of 16, 8, 4, 2 and 1 fC . An additional capacitance of 10 pF is attached at the input node.

enables an A-to-D conversion at the side of a front-end chip and is compatible with a low V_{DD} voltage. The circuit works properly only with a positive charge input. The feedback element of these circuits is operated with a very small current in the order of 5 nA , and is vulnerable to a leakage current of the constant current source. Fig.6 shows the waveform of CHAIN2 for an operation with a bias current of 5 nA for the feedback circuit.

CHAIN3 is accompanied by a circuit as shown in Fig.7 with a feedback capacitor of 0.04 pF . The feedback element has just a minor modification from that of CHAIN2 to employ a capacitor of 0.04 pF for the mirror part of the feedback circuit, which introduces a small overshoot before settling to a base line, and, hence, helps operation of the discriminator circuit located downstream.

CHAIN4 is accompanied by a circuit as shown in Fig.8. CHAIN4 works as a trans-impedance amplifier[5] and is compatible with a high flux environ-

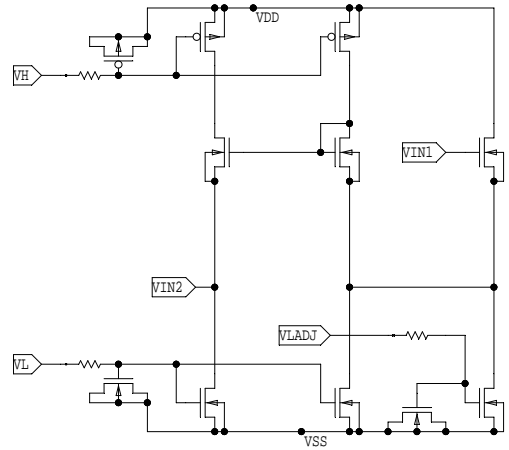


Fig. 5. Schematic of the feedback element for CHAIN2.

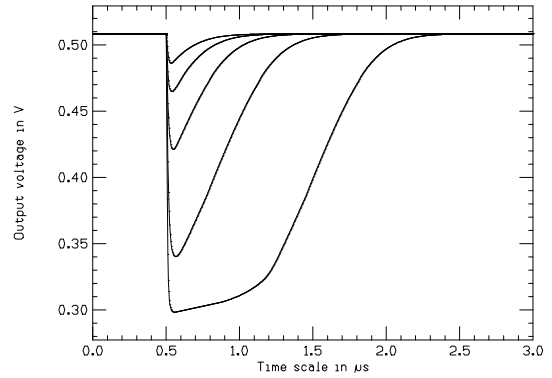


Fig. 6. Waveform of CHAIN2. The feedback circuit is operated with a bias current of 5 nA . The curves are for input charges of 16, 8, 4, 2 and 1 fC . An additional capacitance of 10 pF is attached at the input node.

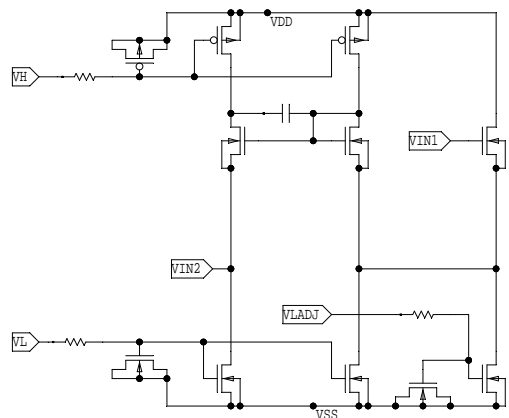


Fig. 7. Schematic of the feedback element for CHAIN3.

ment. Fig.9 shows the waveform of CHAIN4 for an operation with a bias current of 100 nA for the feedback circuit. The feedback circuit for CHAIN4 is operated with a relatively larger current to be robust against the leakage current.

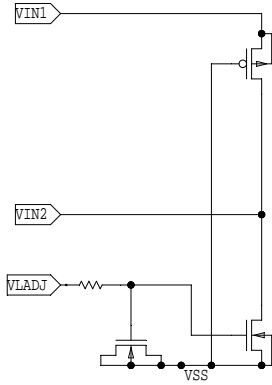


Fig. 8. Schematic of the feedback element for CHAIN4.

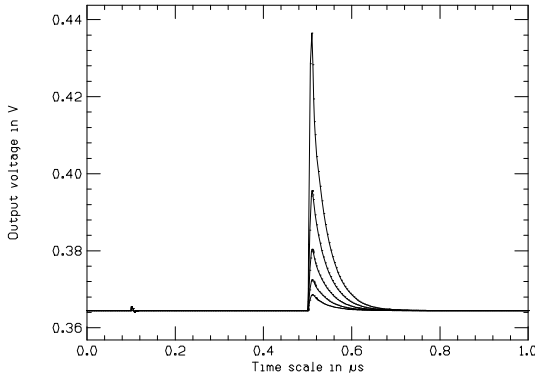


Fig. 9. Waveform of CHAIN4 for negative charge. The feedback circuit is operated with a bias current of 100 nA . The curves are for input charges (negative) of 16, 8, 4, 2 and 1 fC. An additional capacitance of 10 pF is attached at the input node.

3. Circuit evaluation

At the first step of the circuit evaluation it turned out that the ESD protection circuit was leaky, and, then, the preamplifier was saturated. The reason was identified that the ESD circuit was fabricated with a thin oxide transistor instead of a thick oxide transistor. Nominal value of the leakage current of the low VT transistor is $10\text{ nA}/\mu\text{m}$, which is easy to kill the preamplifier circuit. In order to reduce the leakage current of the ESD transistor, we raised the VSS power rail of the ESD transistors, and, then, the preamplifier circuit was recovered.

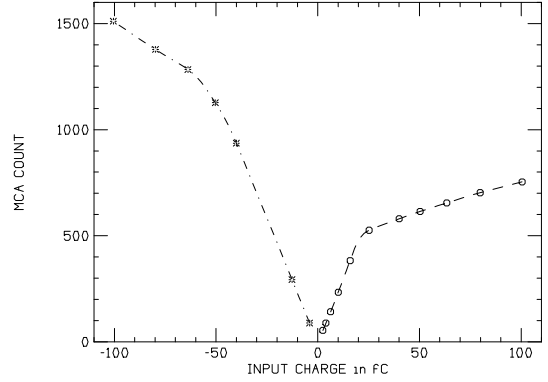


Fig. 10. Response of CHAIN1
The peaking time employed is 500 ns .

Fig.10 shows the response of CHAIN1 circuit chain. CHAIN1 shows a good linearity for the input charge of 20 fC to -50 fC ; the voltage swings were -200 mV , and 500 mV , respectively. In order to characterize the performance, we employed an external shaping amplifier and an MCA equipment. The decay time constant of the preamplifier could be slowed down to 20 μs , but was limited by the leakage current of the feedback circuit.

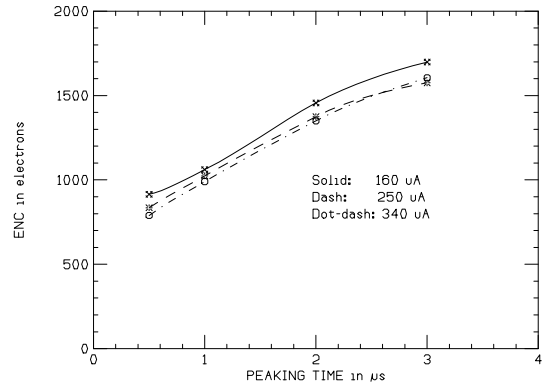


Fig. 11. Equivalent noise charge of CHAIN1 in terms of peaking time. Three curves are for drain currents 160 μA , 250 μA , and 340 μA for the input FET.

Fig. 11 shows the equivalent noise charge in terms of a peaking time. The noise level at the peaking time of 500 ns was $800\text{-}900$ electrons, and increased monotonically for 1, 2 and 3 μs of the peaking time. The tendency was little affected by the drain current of the input FET of the preamplifier. This behavior is understood as coming from the leakage current of the ESD transistors located at the input node of the preamplifier.

Fig. 12 shows the equivalent noise charge in terms of external capacitance attached at the input node

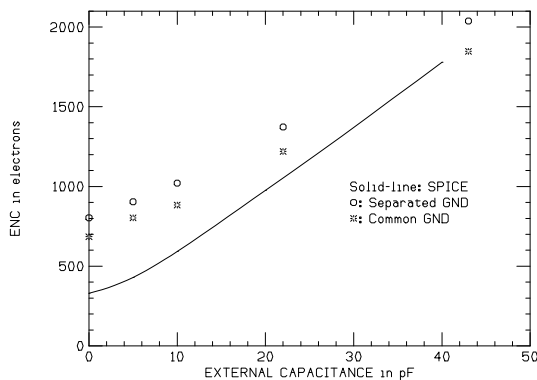


Fig. 12. Equivalent noise charge of CHAIN1 in terms of external capacitance. The peaking time employed is 500 ns with a drain current $340 \mu A$ for the input FET

of the preamplifier. The noise level was slightly affected by the grounding scheme, and was apparently larger than the noise level predicted by a Spice simulation. The excess noise for low capacitance region understood as coming from the leakage current of the ESD transistors.

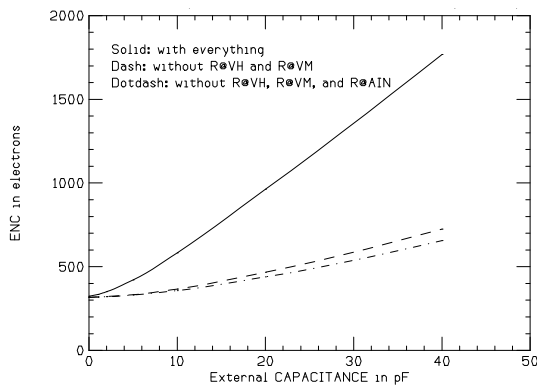


Fig. 13. Spice simulation of the equivalent noise charge. The solid line is for the present design. The dash and dotdash lines depict improvement of the noise level.

In addition to the leakage current of the ESD transistor, an additional noise source was identified. At the last chance of the circuit design, we attached an RC filter at the gate node (VH) of the current source transistor without evaluating the impact on the noise performance. By eliminating the series resistor located at the gate node (VH), we have confirmed that the overall noise level is drastically reduced as shown in Fig.13. The noise contribution of the 50Ω resistor series to the input node of the preamplifier is still minor compare to the above mentioned noise source.

In order to fix the identified issues, a revised design was submitted via VDEC. The detailed evalua-

tion for CHAIN2, CHAIN3, and CHAIN4 are postponed to wait for completion of the new chip.

4. Summary

Deep sub-micron CMOS processes have been widely employed for high-energy physics, astrophysics, and other uses. In order to go beyond existing technologies in analog circuit design, we initiated a design work with an FD SOI process from Oki Electric Industry Co., Ltd. We submitted a TEG design to identify compatibility with the design practices accumulated for a deep sub-micron CMOS, or need to incorporate technologies explored in other research fields. The first TEG design was evaluated to reveal that the front-end circuit with the FD-SOI was promising for a front-end application. On the other hand, some design issues were identified to be fixed for characterizing the FD-SOI circuit in detail. The revised design have already submitted, where included are H-gate transistors for the input FET of the preamplifier circuit to study impact on the radiation tolerance.

Acknowledgements

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